ABSTRACT OF THE INVENTION

The present invention discloses a method and apparatus for testing eye diagram characteristics. The present invention does not utilize a RF analyst used in prior art. On the contrary, the present invention directly sends a precondition from a mainframe to a chip under test, and the GLPF signals are read out from the chip under test. After digitalizing and normalizing the GLPF signals, an eye diagram program stored in the mainframe is executed and the eye diagram is reconstructed. Next, a software analyzer is used to compute an error between the eye diagram parameters and predefined specifications, to determine if the chip under test is in an allowable range of the specification according to the computed error. If the computed error is beyond the allowable range, the chip under test will be discarded.